

A study of (111) oriented epitaxial thin films of In_2O_3 on cubic Y-doped ZrO_2 by synchrotron based x-ray diffraction – ERRATUM

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In the article by Regoutz et al.,¹ a (10 $\bar{2}$ 6) reflection is indicated throughout the text.

The correct reflection is (1026) in all instances.

The publisher regrets the error.

REFERENCE

1. A. Regoutz, K.H.L. Zhang, R.G. Egdell, D. Wermeille, and R.A. Cowley: A study of (111) oriented epitaxial thin films of In_2O_3 on cubic Y-doped ZrO_2 by synchrotron based x-ray diffraction. *J. Mater. Res.* **27**, 2257–2264 (2012) doi: 10.1557/jmr.2012.162.